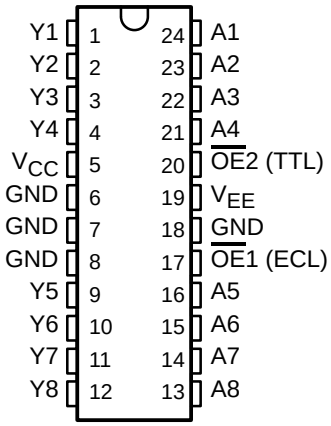
- **100K Compatible**
- **ECL and TTL Control Inputs**
- **Noninverting Outputs**
- **Flow-Through Architecture Optimizes PCB Layout**
- **Center Pin V_{CC}, V_{EE}, and GND Configurations Minimize High-Speed Switching Noise**
- **Package Options Include "Small Outline" Packages and Standard Plastic 300-mil DIPs**

DW OR NT PACKAGE
(T0P VIEW)



description

This octal ECL-to-TTL translator is designed to provide a efficient translation between a 100K ECL signal environment to a TTL signal environment. This device is designed specifically to improve the performance and density of ECL-to-TTL CPU/bus-oriented functions such as memory-address drivers, clock drivers, and bus-oriented receivers and transmitters.

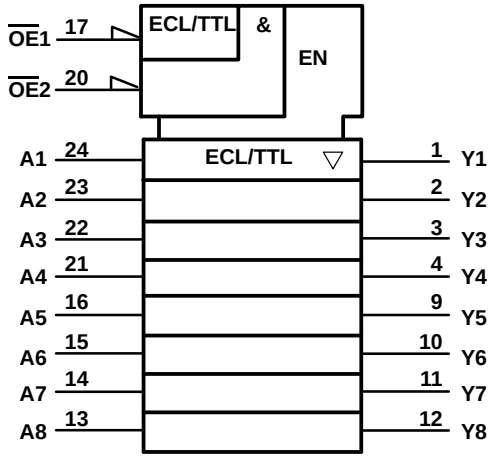
Two output-enable pins, $\overline{OE}1$ and $\overline{OE}2$ are provided. These control inputs are ANDed together with $\overline{OE}1$ being ECL compatible and $\overline{OE}2$ being TTL compatible. This offers the choice of controlling the outputs of the device from either a TTL or ECL signal environment.

The SN100KT5541 is characterized for operation from 0°C to 85°C.

FUNCTION TABLE

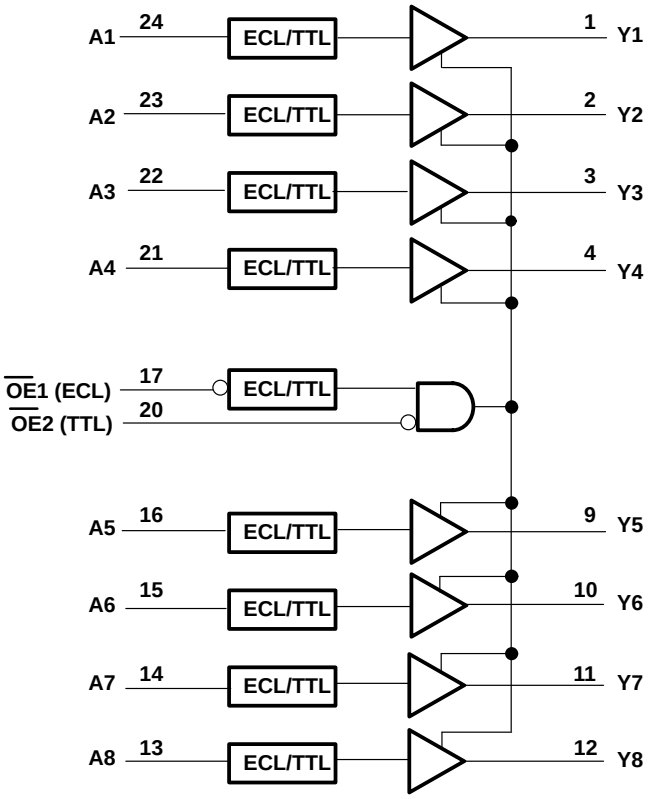
OUTPUT ENABLE		DATA INPUT	OUTPUT (TTL)
$\overline{OE}1$	$\overline{OE}2$	A	Y
X	H	X	Z
H	X	X	Z
L	L	L	L
L	L	H	H

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC} . . . . . –0.5 V to 7 V
Supply voltage range, V_{EE} . . . . . –8 V to 0 V
Input voltage range (TTL) (see Note 1) . . . . . –1.2 V to 7 V
Input voltage range (ECL) . . . . . V_{EE} to 0 V
Voltage applied to any output in the high state . . . . . –0.5 V to V_{CC}
Voltage applied to any output in the disabled or power-off state . . . . . –0.5 V to 5.5 V
Input current range (TTL) . . . . . –30 mA to 5 mA
Current into any output in the low state . . . . . 96 mA
Operating free-air temperature range . . . . . 0°C to 85°C
Storage temperature range . . . . . –65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The TTL input voltage ratings may be exceeded provided the input current ratings are observed.

recommended operating conditions

		MIN	NOM	MAX	UNIT
V_{CC}	TTL supply voltage	4.5	5	5.5	V
V_{EE}	ECL supply voltage	–4.2	–4.5	–4.8	V
V_{IH}	TTL high-level input voltage	2			V
V_{IL}	TTL low-level input voltage			0.8	V
V_{IH}	ECL high-level input voltage‡	–1150		–840	mV
V_{IL}	ECL low-level input voltage‡	–1810		–1490	mV
I_{IK}	TTL input clamp current			–18	mA
I_{OH}	High-level output current			–15	mA
I_{OL}	Low-level output current			48	mA
T_A	Operating free-air temperature	0		85	°C

‡ The algebraic convention, in which the least positive (most negative) value is designated minimum, is used in this data sheet for logic levels only.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS			MIN	TYP†	MAX	UNIT
V_{IK}	$\overline{OE}$2 only	V_{CC} = 4.5 V,	V_{EE} = –4.2 V,	I_I = –18 mA			–1.2	V
I_I	$\overline{OE}$2 only	V_{CC} = 5.5 V,	V_{EE} = –4.8 V,	V_I = 7 V			0.1	mA
I_{IH}	$\overline{OE}$2 only	V_{CC} = 5.5 V,	V_{EE} = –4.8 V,	V_I = 2.7 V			20	µA
I_{IL}	$\overline{OE}$2 only	V_{CC} = 5.5 V,	V_{EE} = –4.8 V,	V_I = 0.5 V			–0.5	mA
I_{IH}	Data inputs and $\overline{OE}$1	V_{CC} = 5.5 V,	V_{EE} = –4.8 V,	V_{IH} = –840 mV			350	µA
I_{IL}	Data inputs and $\overline{OE}$1	V_{CC} = 5.5 V,	V_{EE} = –4.8 V,	V_{IL} = –1810 mV	0.50			µA
V_{OH}		V_{CC} = 4.5 V,	V_{EE} = –4.5 V ± 0.3 V,	I_{OH} = –3 mA	2.4	3.3		V
		V_{CC} = 4.5 V,	V_{EE} = –4.5 V ± 0.3 V,	I_{OH} = –15 mA	2	3.1		
V_{OL}		V_{CC} = 4.5 V,	V_{EE} = –4.5 V ± 0.3 V,	I_{OL} = 48 mA		0.38	0.55	V
I_{OZH}		V_{CC} = 5.5 V,	V_{EE} = –4.8 V,	V_O = 2.7 V			50	µA
I_{OZL}		V_{CC} = 5.5 V,	V_{EE} = –4.8 V,	V_O = 0.5 V			–50	µA
I_{OS}‡		V_{CC} = 5.5 V,	V_{EE} = –4.8 V,	V_O = 0 V	–100		–225	mA
I_{CCH}		V_{CC} = 5.5 V,	V_{EE} = –4.8 V			64	97	mA
I_{CCL}		V_{CC} = 5.5 V,	V_{EE} = –4.8 V			80	120	mA
I_{CCZ}		V_{CC} = 5.5 V,	V_{EE} = –4.8 V			77	116	mA
I_{EE}		V_{CC} = 5.5 V,	V_{EE} = –4.8 V			–22	–33	mA
C_i		V_{CC} = 5 V,	V_{EE} = 4.5 V			5		pF
C_o		V_{CC} = 5 V,	V_{EE} = 4.5 V			7		pF

† All typical values are at V_{CC} = 5 V, V_{EE} = –4.5 V, T_A = 25°C.
‡ Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (see Figure 1)

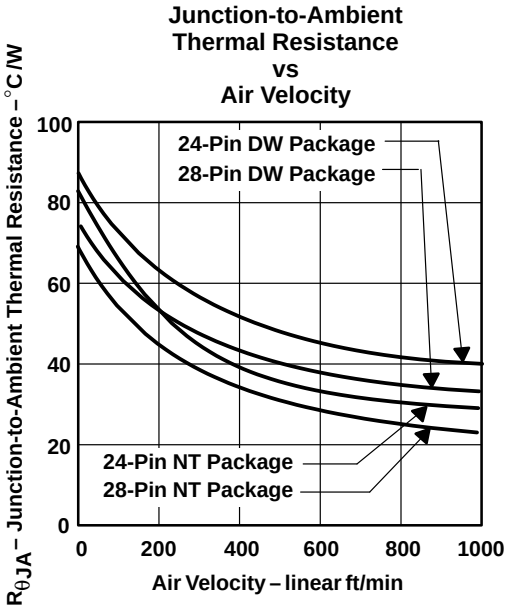
PARAMETER	FROM (INPUT)	TO (OUTPUT)	C_L = 50 pF, R1 = 500 Ω, R2 = 500 Ω			UNIT
			MIN	TYP§	MAX	
t_{PLH}	A	Y	1.7	4	6.2	ns
t_{PHL}			1.6	4	6.2	
t_{PZH}	$\overline{OE}$1	Y	2.6	4.7	6.7	ns
t_{PZL}			3.2	5.9	8.5	
t_{PHZ}	$\overline{OE}$1	Y	2.9	5.4	7.8	ns
t_{PLZ}			1.9	4.9	7.8	
t_{PZH}	$\overline{OE}$2	Y	1.7	4	6.2	ns
t_{PZL}			2.5	5.1	7.7	
t_{PHZ}	$\overline{OE}$2	Y	2.1	4.3	6.4	ns
t_{PLZ}			1.1	3.7	6.3	

§ All typical values are at V_{CC} = 5 V, V_{EE} = –4.5 V, T_A = 25°C.

THERMAL INFORMATION

In digital system designs utilizing 100KT' or 10KHT' series logic level translators, good thermal management is an important consideration for proper circuit performance and extended reliability. The size of the "small outline" package makes thermal management even more important due to the increased board and thermal densities.

The thermal resistances in Figure 1 can be used to approximate typical and maximum virtual junction temperatures for the SN100KT' and SN10KHT' translators. The junction temperature of these devices may be estimated using Equation 1.

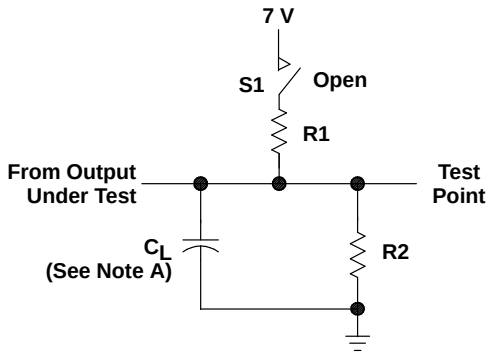


$$T_J = R_{\Theta JA} (V_{CC} \bullet I_{CC} + V_{EE} \bullet I_{EE} + P_{DRIVER}) + T_A \quad (1)$$

where

T_J = virtual junction temperature
T_A = ambient air temperature
$R_{\Theta JA}$ = thermal resistance, junction to ambient air
I_{CC} = TTL level supply current (from the databook)
I_{EE} = ECL supply current
V_{CC} = TTL level suply voltage (5 V for typical, 5.5 V for maximum)
V_{EE} = ECL level supply voltage:
SN10KHT' – (–5.2 V Typ, –5.46 V Max)
SN100KHT' – (–54.5 V Typ, –4.80 V Max)
P_{DRIVER} = total power consumed by the output driver

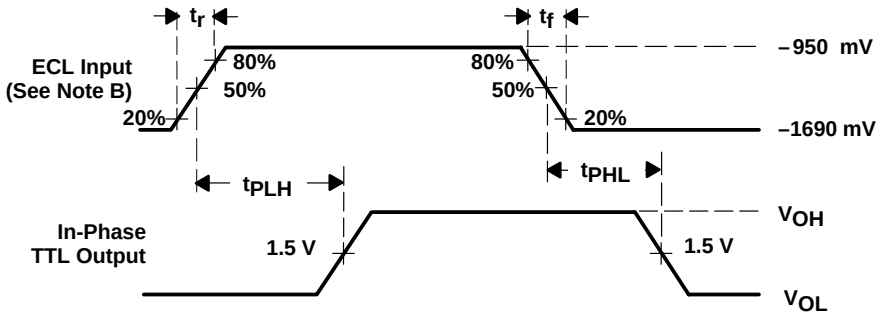
PARAMETER MEASUREMENT INFORMATION



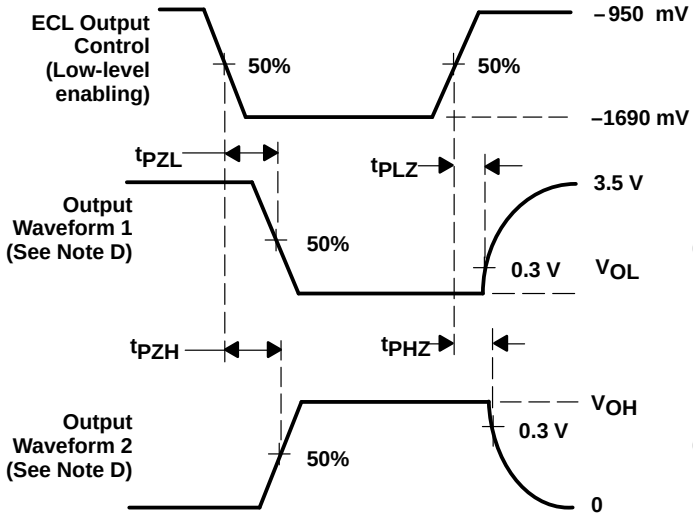
LOAD CIRCUIT

SWITCH POSITION TABLE

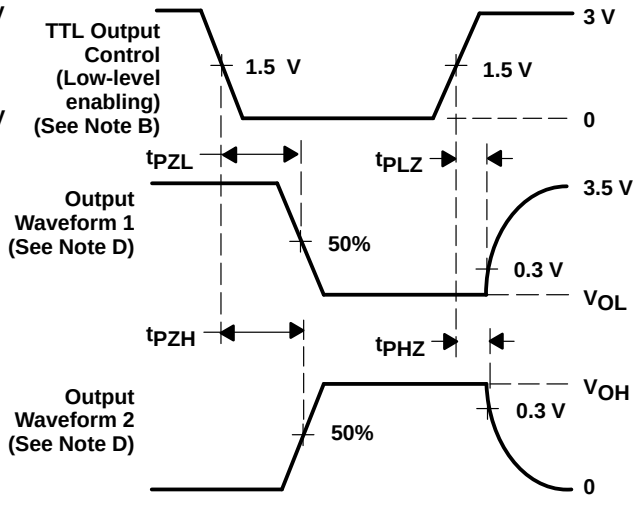
TEST	S1
t_{PLH}	Open
t_{PHL}	Open
t_{PZH}	Open
t_{PZL}	Closed
t_{PHZ}	Open
t_{PLZ}	Closed



ECL- INPUT PROPAGATION DELAY TIMES



ECL ENABLE AND DISABLE TIMES



TTL ENABLE AND DISABLE TIMES

NOTES: A. C_L includes probe and jig capacitance.
B. For TTL inputs, input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r ≤ 2.5 ns, t_f ≤ 2.5 ns.
C. For ECL inputs, input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r ≤ 1.5 ns, t_f ≤ 1.5 ns.
D. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

IMPORTANT NOTICE

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.